


<b>Search Notes</b>  	<b>Application/Control No.</b>  10826480	<b>Applicant(s)/Patent Under Reexamination</b>  APPARAO ET AL.
	<b>Examiner</b>  Ehichioya, Fred I	<b>Art Unit</b>  2162

SEARCHED			
Class	Subclass	Date	Examiner
707	1, 10, 100, 102, 104.1, 200	4/12/08	FE
709	224, 245	4/12/08	FE
715	745, 748	4/12/08	FE

SEARCH NOTES		
Search Notes	Date	Examiner
East (US-PGPub, USPat, EPO, JPO, Derwent).text search only	8/20/07	FE
East (US-PGPub, USPat, EPO, JPO, Derwent).text search updated	11/10/07	FE
East (US-PGPub, USPat, EPO, JPO, Derwent).class/subclass and text search	4/12/08	FE
ACM	4/12/08	FE
IEEE	4/12/08	FE
Google.com	4/12/08	FE

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
709	224 - see search history	4/12/08	FE